

**HYBRID DYNAMIC PHASE ALIGNMENT  
SCHEME TO IMPROVE SAMPLING  
RESOLUTION FOR 1.25 GHZ SOURCE  
SYNCHRONOUS INTERFACE**

**By**

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## List of Abbreviations

<b>Abbreviation</b>	<b>Meaning</b>
8B/10B	8 bits/10 bits
BBPD	Bang-Bang Phase Detector
CDR	Clock and Data Recovery
DC	Direct Current
DFF	D Flip-Flop
DLL	Delay Lock Loop
DPA	Dynamic Phase Alignment
EMI	Electromagnetic Interference
FIFO	First In First Out
Gbps	Giga bits per second
GMII	Gigabit Media Independent Interface
I/O	Input/output
LPF	Low Pass Filter
LVC MOS	Low Voltage Complementary Metal Oxide Semiconductor
LVDS	Low Voltage Differential Signaling
LVTTL	Low Voltage Transistor-Transistor Logic
MHz	Mega Hertz
PCB	Printed Circuit Board
PD	Phase Detector
PLL	Phase Lock Loop
PnR	Place and Route
PRBS	Pseudo Random Binary Sequence
ps	pico second
PVT	Process, Voltage and Temperature
RG MII	Reduced Gigabit Media Independent Interface
Rx	Receive
SEIO	Single Ended Input/Output
SerDes	Serializer/Deserializer
SG MII	Serial Gigabit Media Independent Interface
TSMC	Taiwan Semiconductor Manufacturing Company
TTL	Transistor-Transistor Logic
Tx	Transmit
TT	Typical-Typical
UI	Unit Interval
VCO	Voltage Controlled Oscillator

# **SKIM PENJAJARAN FASA DINAMIK HIBRID UNTUK MENINGKATKAN RESOLUSI PERSAMPELAN BAGI ANTARAMUKA SUMBER SEGERAK**

**1.25 GHZ**

## **Abstrak**

Penjajaran fasa dinamik (DPA) telah digunakan secara meluas dalam antaramuka sumber segerak untuk mencapai titik persampelan yang optimum. Pada frekuensi yang lebih tinggi, penganggaran masa akan menjadi lebih ketat. Oleh itu, DPA perlu mencapai resolusi persampelan yang lebih kecil untuk menyediakan bajet masa yang lebih baik untuk antaramuka sumber segerak. Teknik DPA yang sedia ada menunjukkan batasan sama ada dari resolusi persampelan atau hasil litar yang kompleks dan ukuran besar. Oleh itu, skim DPA yang baru diperlukan untuk mencapai resolusi persampelan yang lebih baik dan mengekalkan kemudahan dalam litar pelaksanaan. Selain itu, DPA juga perlu berupaya untuk memantau hubungan antara isyarat data dan jam serta memperbaharui konfigurasi litar secara berterusan. Kajian telah dijalankan untuk membina litar DPA yang memenuhi semua keperluan di atas. Litar DPA yang dibina adalah hasil penggabungan skim persampelan yang menggunakan konsep berbilang fasa yang sedia ada dan juga teknik persampelan lengah talian berbilang tap. Keputusan simulasi menunjukkan bahawa skim yang dicadangkan dapat mencapai 43 ps resolusi persampelan berbanding dengan 78 ps resolusi persampelan yang dicapai oleh skim yang sedia ada. Skim yang dicadangkan juga mengekalkan kesederhanaan dari segi binaan litar kerana kebanyakan komponen litar dibina menggunakan komponen digital. Daripada simulasi yang telah dilaksanakan, litar ini juga menunjukkan keupayaan untuk menyelaraskan fasa data dan isyarat jam secara dinamik dari semasa ke semasa.

# **HYBRID DYNAMIC PHASE ALIGNMENT SCHEME TO IMPROVE SAMPLING RESOLUTION FOR 1.25 GHZ SOURCE SYNCHRONOUS INTERFACE**

## **Abstract**

Dynamic phase alignment (DPA) circuit has been widely used in source synchronous interface to achieve an optimal sampling point. At higher frequency, the timing requirement will become more stringent. Therefore, the DPA circuit needs to achieve finer sampling resolution to provide a better timing budget for the source synchronous interface. Existing DPA techniques have shown the limitation either on the sampling resolution or potentially large and complex circuit implementation. Due to this, a new DPA scheme is needed in order to achieve better sampling resolution and at the same time keep the simplicity in the circuit implementation. Beside the timing consideration, DPA also need to be able to monitor relation between the data and clock continuously and adjust the setting dynamically. A study has been conducted to develop an improved version of DPA circuit that meets all the requirements above. The improved DPA circuit is implemented by combining the existing multi-phase sampling scheme and also the multi-tap delay line sampling technique. Simulation results show that the proposed design able to achieve 43 ps sampling resolution compares to 78 ps sampling resolution achieves by the existing scheme. The proposed design keeps the simplicity of the circuit by using the digital blocks to construct most of the circuit components. From the performed simulations, the circuit also shows the capability to dynamically phase align the data and clock signals from time to time.

# CHAPTER 1

## INTRODUCTION

### 1.1 Background

Serial data transmission is used in the majority of today's interconnect and data transmission system due to its simplicity and minimum hardware requirement. This is especially true with the explosion of data, voice and video traffic across many markets. The serial data interface can be divided into asynchronous transmission and also synchronous transmission.

For asynchronous serial transmission, only data bits sent from the transmission source to the receiver end. A clock and data recovery block (CDR) is normally used to regenerate the clock signal from the data stream and used it to sample the incoming data bits. Plenty of solutions have been invented but most of today's CDR system is implemented using phase-locked loop (PLL) and delay lock loop (DLL) circuitry (Lee and Bulzacchelli, 1992; Sang-Ho, Hyung-Min et al., 2010).

As for synchronous serial transmission, a reference clock is sent together with the data from the transmission source. For these source-synchronous interfaces, clock and data signals skew need to be kept minimum. Keeping the clock and data signals phase aligned can be difficult when dealing with the board, package and on-

die effects such as skew, jitter, and noise (Altera Corporation, 2004). In order to minimize such effects, a phase alignment scheme is needed to achieve high bandwidth applications.

Phase alignment can be categorized into 2 main groups: static phase alignment and dynamic phase alignment (DPA). For static phase alignment, designer need to carefully match the data and the clock path on the board, package and also on-die routing. This approach is labor-intensive, time consuming and difficult due to the today's high pin count device (Altera Corporation, 2004). On the other side, DPA have been developed to improve the static phase alignment method. DPA block will realign the incoming data with respect to the clock edge. The clock edge will shift to the center of the data eye which in return increase the timing margin of a system and result in higher bandwidth support (Khor, Hoo et al., 2007). DPA system will normally perform a multiple data stream sampling before the circuitry can find out the optimal clock phase or delay setting used to realign the data and clock signals. The routing mismatch between the data and clock path for each receiver channel can be compensated by the DPA block individually and automatically if the DPA blocks being integrated into each receiver channel (Venkata, Wong et al., 2003). The designers can save the effort from manually match the routing skew for each pin and accelerating the time to market for new products by doing this.

### **1.1.1 Problem Statements**

Timing budget is the account of timing requirements or timing parameters necessary for a system to function properly. For source synchronous interface design, the timing requirement must fit within a single clock cycle. The timing parameters

involve many factors, including setup and hold time requirement, channel to channel skew requirement, jitter performance and also maximum operating frequency requirement. For an ideal case scenario, the clock signal need to sample the data at the exact center point of the data bit interval in order to obtain a maximum timing margin for the mentioned timing parameters. The timing margin introduces by multi-phase sampling scheme described in (Chang and Starr, 2009) and (Burney, 2010) is limited by the number of clock phases provided by PLL. Increase the number of clock phase can achieve better sampling resolution. However, there is a tradeoff for increasing the clock phases as the complexity of PLL design will increase accordingly.

On the other hand, multi-tap delay line sampling scheme described in (Yeoh, 2009) may provide better sampling resolution than the PLL-based dynamic phase adjustment circuit. The improved sampling resolution is achieved by using delay elements with small propagation delay for each delay tap. However, since the data and the clock signal phase relation are unknown for source synchronous interface, a large set of delay elements need to be built in order to compensate for a full clock cycle period. As the result, the total number of delay elements and the associated logic could force the dynamic phase alignment circuit to be quite huge.

In short, both dynamic phase alignment schemes showing disadvantage either on the sampling resolution or large and complex circuit design. Therefore, a new dynamic phase adjustment circuit is needed to achieve better sampling resolution without being inordinately large and complex.

## **1.2 Objective**

This research will propose a new hybrid dynamic phase alignment circuit which will be used on the receiver side of source synchronous interface. The proposed circuit combines both the multi-phase and multi-tap delay line sampling schemes. This research has the following objectives:

1. To investigate a suitable dynamic phase alignment scheme to be used in source synchronous interface.
2. To propose a hybrid phase alignment scheme at the receiver side to achieve better sampling resolution compare to existing multi-phase sampling scheme and multi-tap delay line sampling scheme.
3. To achieve real time dynamic alignment to compensate for any data to clock skew from time to time.

## **1.3 Project Scopes**

The receiver for source synchronous serial interface contains input pins, sampling units and also the deserializer. The scope of this research will only focus on the software implementation of the sampling unit. The sampling unit will be implemented using both multi-phase and multi-tap delay line sampling schemes. The target performance of this circuit is 1.25 GHz toggle rates.

## **1.4 Research Contribution**

This project will contribute a new dynamic phase alignment scheme by combining the existing multi-phase and multi-tap delay line sampling schemes. The proposed dynamic phase alignment circuit can be used to sample the incoming data at the receiver side of the serial interface. This new method will improve the sampling resolution over the traditional multi-phase sampling scheme and at the same time maintain the simplicity compare to the conventional delay tap sampling scheme.

## **1.5 Thesis Organization**

The remainder of this thesis is organized into four chapters as follows.

Chapter 2 discusses relevant literature review focusing on the two main phase alignment scheme which is a multi-phase sampling and also the multi-tap delay line sampling schemes. The chapter begins by showing the evolution of the serial interface system and also the issues and concerns regarding the serial interface implementation. Examples of the multi-phase sampling circuit and multi-tap delay line sampling circuit used in industry will be presented and discussed in detail.

Chapter 3 discussed the development of the proposed dynamic phase alignment circuit. This chapter will be break down according to each sub-module built in the dynamic phase alignment circuit. The functionality and implementation for each sub-module will be discussed in detail. This chapter concludes with a combination of all the sub-modules to form a complete dynamic phase alignment system.

Chapter 4 discusses and analyses the simulation and measurement results. This chapter starts off with the introduction to the software tools and technology process used in this project. It is continued with the functionality and timing result verification to ensure the built logic behaves and function correctly.

The final chapter, Chapter 5 consists of conclusions and future works. The conclusion will cover the key highlights of the findings and contributions of the research while some recommendations and ideas for future works are proposed.

## **CHAPTER 2**

### **LITERATURE REVIEW**

Chapter 1 explains the necessity and also the advantages of implementing the DPA block inside the source synchronous interface design. The current DPA designs show limitation either on the sampling resolution or the complexity in the circuit implementation. Therefore a hybrid DPA scheme has been proposed to achieve better sampling resolution and reduce the complexity in the circuit implementation. To complement the first chapter, Chapter 2 presents the prior art design that used for the source synchronous interface and the literature review that relates to the existing DPA architecture.

#### **2.1 Evolution of Serial Interface**

This section will discuss the development of serial interface in the industry. The section will be concluded by using the Gigabit Ethernet as an example to show the evolution of the serial interface.

##### **2.1.1 Parallel Interface**

In the earlier system design, the simplest method of data transmission across different chip is to directly connect the data path from one chip to the next chip in the parallel format. The data path often consists more than one bit of information to form a system interface. For a complex interface design, hundred of pins may be

required in order to transfer the information from one chip to another chip. This also raises the issue on how many input/output (I/O) pins that can be fit into a single chip. Due to the Moore's Law prediction, more and more circuits can be manufactured into a single chip compare few decades ago. However, pin density of chip packaging has not increased at the same rate as the silicon density which creates a scenario where the package I/O pins are more expensive than silicon circuits (Stauffer, 2008). Besides the package consideration, printed circuit board (PCB) design also shows cost increasing due to the excessive pin count that take up extra space. Figure 2.1 shows the I/O trends for semiconductor devices.

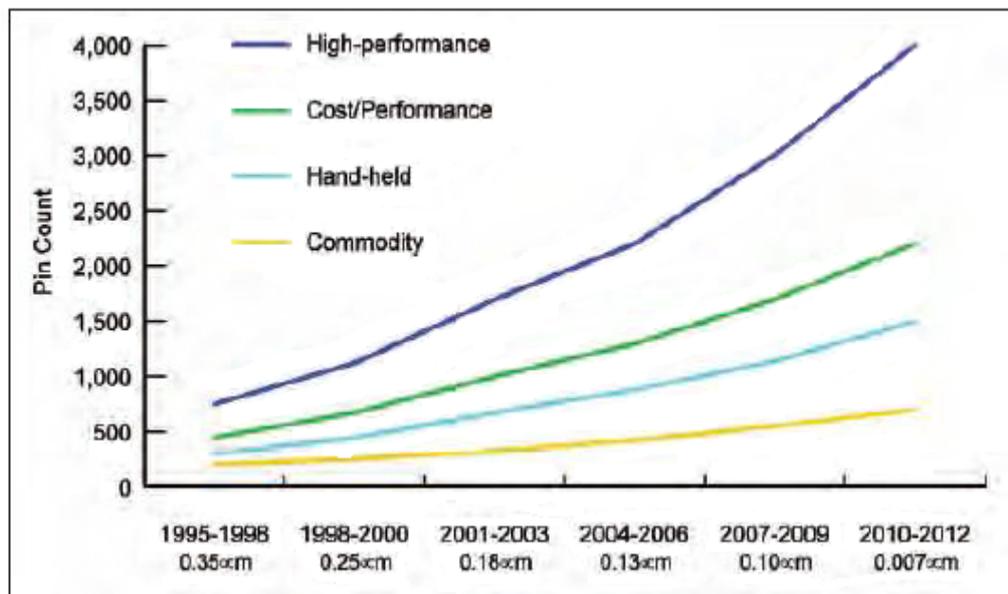


Figure 2.1: I/O Trends for Semiconductor Devices (Holden, Andresakis et al., 2009)

Furthermore, the nature of a parallel connection requires the data traveling across all the pins to send out from the device simultaneously and also arrived at the other device at the same time. To meet this difficult synchronization requirement, designer must design each pin trace the exact same length. With the excessive pin count introduces by the parallel interface, it is difficult for the designer to exactly match each path with the same length due to the space concern (Lund, 2002). Pin

trace of differing length creates channel skew which can directly degrade the interface transfer rate.

### **2.1.2 High Speed Parallel Interface**

The issue of integrated excessive pin count into a single device will become more significant over time as shown in Figure 2.1. A simple way to correct this problem is to use fewer pins. In order to achieve this goal, designer started to push the interface toggle rate to much higher speed. With higher toggle rate, same amount of data can be completely sent to the destination by using fewer pin. This approach offers some advantages but does not solve all of the issues arise from using the parallel interface. Fewer pins reduce the package and the PCB cost which makes the designs more competitively priced. On top of that, few pins make it easier to synchronize all the signals so the data can be sent and received synchronously.

However, the increase of frequency for each trace results some trade off. One of the concerns is the electromagnetic interference (EMI) between the traces. The EMI is caused by the Single Ended I/O (SEIO) standard used by the parallel interface. An example of the SEIO standard used in the industry is Low Voltage Transistor-Transistor Logic (LVTTTL) and Low Voltage Complementary Metal Oxide Semiconductor (LVCMOS) (JEDEC, 2006). These standards will create interference issues due to the higher current inject into each trace as the result of higher toggle rate (Lund, 2002; Bogatin, 2004). The signal integrity issue caused by the EMI can degrade or limit the effective performance of the circuit. This problem can be solved by adding more space between the traces or fully shield each and

every trace to eliminate the interference. These approaches defeat the goal of increasing the pin toggle rates.

### **2.1.3 Migration to Serial Interface**

The next solution to the parallel interface issue is to shift from a parallel interface to a serial interface. Few data streams will be combined into a single data stream and send through the interface using much higher speed. At the receiver end, the data stream will be further broken down to form parallel of signals again before sending out to the processing unit. These operations normally involve the Serializer and Deserializer (SerDes) circuitry. One of the important factors that enable this operation is the used of the Low-Voltage Differential Signaling (LVDS) standard. The LVDS technology allows the signal transfer at Gigabits per second compare to the LVTTTL/LVCMOS which only allow a few hundred of Megabits per second transfer rate (Texas Instruments, 2002). Beside the higher toggle rate, the LVDS standard also help to reduce the EMI due to the field coupling within the differential pair (Cole, 2002).

Table 2.1 shows the evolution of serial interface using the Gigabit Ethernet designs as an example. Gigabit Media Independent Interface (GMII) is a standard used to achieve transfer rates up to 1 Gigabit per second in Ethernet network (Fifield, 1997). Due to the parallel interface architecture, total 12 receive signals (Rx) and 12 transmit signals (Tx) are required. To reduce the GMII pin count, Reduced Gigabit Media Independent Interface (RGMII) has been introduced (Alto, 2002). RGMII uses half the number of data pins as used in the GMII interface. This reduction is achieved by clocking the data at both rising edge and falling edge of the

clock signal. Although the RGMII standard reduced the pin count by half, but this standard suffers from the EMI issue due to the higher toggle rate. Following the RGMII standard, Serial Gigabit Media Independent Interface (SGMII) has been introduced (Chu, 2001). This interface uses the LVDS standard and the transfer rate can achieve up to 1.25 Gigabit per second. Due to the nature of differential signaling used by the LVDS standard, the effect of EMI has been greatly reduced. SGMII only uses single data stream to transfer the data. However due to the differential standard, 2 I/O pins will be used for transmit and receive side.

Table 2.1: Comparison of Gigabit Ethernet Designs

	GMII	RGMII	SGMII
I/O Standard	LVTTL	LVTTL	LVDS
Pin Count	12 Rx, 12 Tx	6 Rx, 6Tx	4 Rx, 4 Tx
Transfer Rate	125Mbps	250Mbps	1.25Gbps
Comparison	Parallel Interface. Highest pin count requirement	Parallel Interface. Medium pin count requirement. Signal Integrity concern due to EMI	Serial Interface. Lowest pin count requirement. Reduce EMI effect due to differential signaling.

## 2.2 Serial Interface Design

Serial Interface can be divided into 2 different categories: asynchronous serial interface and source synchronous serial interface. This section will discuss briefly on the asynchronous interface design and more focus will be put on the synchronous interface design.

### 2.2.1 Asynchronous Serial Interface Design

In asynchronous serial interface, data are transmitted without the clock signal. In fact, the clock signal is embedded inside the data stream that sent out from

the transmitter. A clock data recovery (CDR) circuit is required to extract the clock information out of the data stream. Figure 2.2 shows the example of clock data recovery block diagram. The CDR consists of phase lock loop (PLL) and decision circuit. The PLL consists of phase detector (PD), charge pump, low pass filter (LPF) and voltage control oscillator (VCO). The PD will detect the clock phase from the data stream and output the control signal to the VCO to regenerate the clock signal. The generated clock signal is used to sample the data inside the decision circuit. The decision circuit will decide if the optimal sampling point has been achieved. Beside the PLL based CDR circuit, CDR can be implemented through the delay lock loop (DLL) as well. Example of CDR design based on DLL (Lee and Bulzacchelli, 1992), oversampling technique (Ahmed and Kwasniewski, 2005), and improved oversampling technique (van Ierssel, Sheikholeslami et al., 2007).

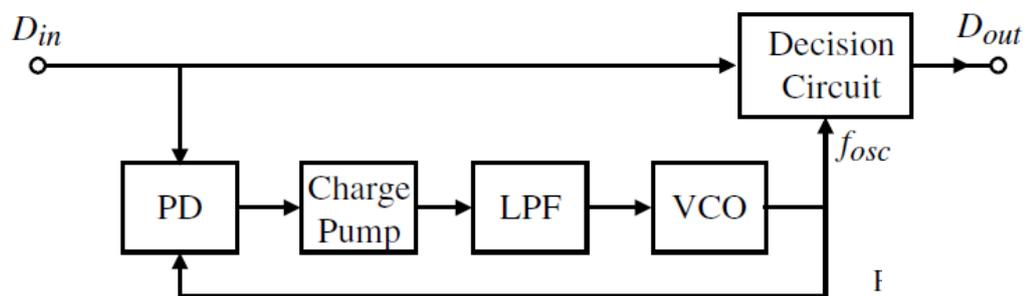


Figure 2.2: Data Recovery with PLL (Allen, 2003)

### 2.2.2 Source Synchronous Serial Interface Design

In contrast from asynchronous interface, data is transmitted together with the clock signal in source synchronous serial interface. Therefore the clock recovery unit is not needed for source synchronous serial interface design. Figure 2.3 shows a simple source synchronous interface. Since the clock signal is common for

transmitter and receiver, designer only need to ensure the traces between data and clock signals is closely matched in order to get the correct sampling data at the receiver side.

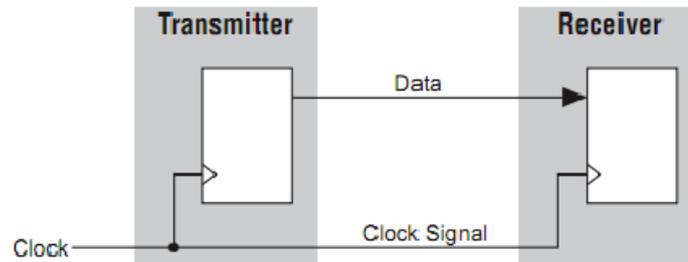


Figure 2.3: Simple Source Synchronous Interface

In order to minimize the skew difference between the data and clock signals, a phase alignment scheme has been introduced to achieve high bandwidth application. As described in Chapter 1, the phase alignment can be categorized into 2 categories which are the static phase alignment and dynamic phase alignment (DPA). For the static phase alignment, designer have to perform manual work to ensure the data and clock signals route is closely matched on the die, on the package and also on board. This work is labor intensive, time consuming and difficult due to the high pin count device (Altera Corporation, 2004). Furthermore, by using the static phase alignment the route matching effort needs to be repeated for each new design.

On the other hand, DPA involve a circuit implementation at the receiver side to adjust the skew between the data and clock signals. By implementing the DPA circuit into each receiver channel, the skew between the data and clock signals will be compensated by the DPA circuit dynamically. Due to this, designers do not need to spend the effort to optimize each signal path to ensure the routing is matched to